2SC1317, 2SC1318

Silicon NPN epitaxial planar type

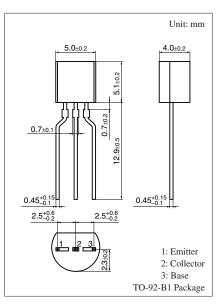
For low-frequency power amplification and driver amplification Complementary to 2SA0719 and 2SA0720

Features

- \bullet Low collector-emitter saturation voltage $V_{CE(sat)}$
- Complementary pair with 2SA0719 and 2SA0720

Parameter	Symbol	Rating	Unit	
Collector-base voltage	2SC1317	V _{CBO}	30	V
(Emitter open)	2SC1318		60	
Collector-emitter voltage	2SC1317	V _{CEO}	25	V
(Base open)	2SC1318		50	
Emitter-base voltage (Col	V _{EBO}	7	V	
Collector current	I _C	0.5	А	
Peak collector current	I _{CP}	1	А	
Collector power dissipation	P _C	625	mW	
Junction temperature	Tj	150	°C	
Storage temperature	T _{stg}	-55 to +150	°C	

Absolute Maximum Ratings $T_a = 25^{\circ}C$



Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

	Symbol	Conditions	Min	Тур	Max	Unit
2SC1317	V _{CBO}	$I_{\rm C} = 10 \ \mu A, \ I_{\rm E} = 0$	30			V
2SC1318			60			
2SC1317	V _{CEO}	$I_{\rm C} = 10 \text{ mA}, I_{\rm B} = 0$	25			V
2SC1318			50			
Emitter-base voltage (Collector open)		$I_{\rm E} = 10 \ \mu A, \ I_{\rm C} = 0$	7			V
Collector-base cutoff current (Emitter open)		$V_{CB} = 20 \text{ V}, I_E = 0$			0.1	μΑ
Forward current transfer ratio *1		$V_{CE} = 10 \text{ V}, I_C = 150 \text{ mA}$	85		340	_
	h _{FE2}	$V_{CE} = 10 \text{ V}, I_C = 500 \text{ mA}$	40			
Collector-emitter saturation voltage *1		$I_{\rm C} = 300 \text{ mA}, I_{\rm B} = 30 \text{ mA}$		0.35	0.60	V
age *1	V _{BE(sat)}	$I_{\rm C} = 300 \text{ mA}, I_{\rm B} = 30 \text{ mA}$		1.1	1.5	V
	f _T	$V_{CB} = 10 \text{ V}, I_E = -50 \text{ mA}, f = 200 \text{ MHz}$		200		MHz
Collector output capacitance (Common base, input open circuited)		$V_{CB} = 10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		6	15	pF
	2SC1318 2SC1317 2SC1318 etor open) nitter open) o *1 voltage *1 age *1	$\begin{array}{c c} 2SC1317 \\ \hline 2SC1318 \\ \hline \\ \hline 2SC1318 \\ \hline \\ \hline \\ 2SC1317 \\ \hline \\ 2SC1318 \\ \hline \\ \hline \\ 2SC1318 \\ \hline \\ \hline \\ \\ \hline \\ 2SC1318 \\ \hline \\ \hline \\ \\ \\ \hline \\ \\ \hline \\ \hline \\ \\ \hline \\ \hline \\ \hline \\ \\ \hline \\ \hline \\ \\ \hline \\ \hline \\ \hline \\ \\ \hline \\ \hline \\ \hline \\ \hline \\ \\ \hline \hline \\ \hline \\ \hline \hline \\ \hline \\ \hline \\ \hline \hline \\ \hline \\ \hline \hline \\ \hline \\ \hline \hline \\ \hline \hline \\ \hline \\ \hline \hline \\ \hline \\ \hline \hline \hline \\ \hline \hline \\ \hline \hline \\ \hline \hline \hline \\ \hline \hline \hline \\ \hline \hline \\ \hline \hline \\ \hline \hline \hline \\ \hline \hline \\ \hline \hline \hline \\ \hline \hline \hline \\ \hline \hline \\ \hline \hline \hline \hline \hline \hline \\ \hline \hline \hline \hline \hline \hline \hline \\ \hline \hline \hline \hline \hline \hline \hline \hline \\ \hline \hline$	$ \begin{array}{c c} 2SC1317 \\ \hline 2SC1318 \\ \hline \\ U_{CEO} \\ \hline \\ 2SC1318 \\ \hline \\ U_{CEO} \\ \hline \\ U_{CE} = 10 \text{ mA, } I_{E} = 0 \\ \hline \\ U_{CE} = 10 \text{ mA, } I_{E} = 0 \\ \hline \\ U_{CE} = 10 \text{ mA, } I_{C} = 0 \\ \hline \\ U_{CB} \\ \hline \\ U_{CB} \\ \hline \\ U_{CB} \\ \hline \\ U_{CB} \\ \hline \\ U_{CE} = 20 \text{ V, } I_{E} = 0 \\ \hline \\ U_{CE} = 10 \text{ V, } I_{C} = 150 \text{ mA} \\ \hline \\ \hline \\ H_{FE2} \\ \hline \\ V_{CE} = 10 \text{ V, } I_{C} = 500 \text{ mA} \\ \hline \\ U_{CE} (sat) \\ \hline \\ U_{CE} (sat) \\ \hline \\ U_{CB} = 10 \text{ V, } I_{E} = 30 \text{ mA} \\ \hline \\ U_{CB} = 10 \text{ V, } I_{E} = -50 \text{ mA, } f = 200 \text{ MHz} \\ \hline \\ U_{CB} \\ \hline \\ U_{CB} = 10 \text{ V, } I_{E} = 0, f = 1 \text{ MHz} \\ \hline \end{array} $	$\begin{array}{c c c c c c c c c c c c c c c c c c c $	$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	$ \begin{array}{c c c c c c c c c c c c c c c c c c c $

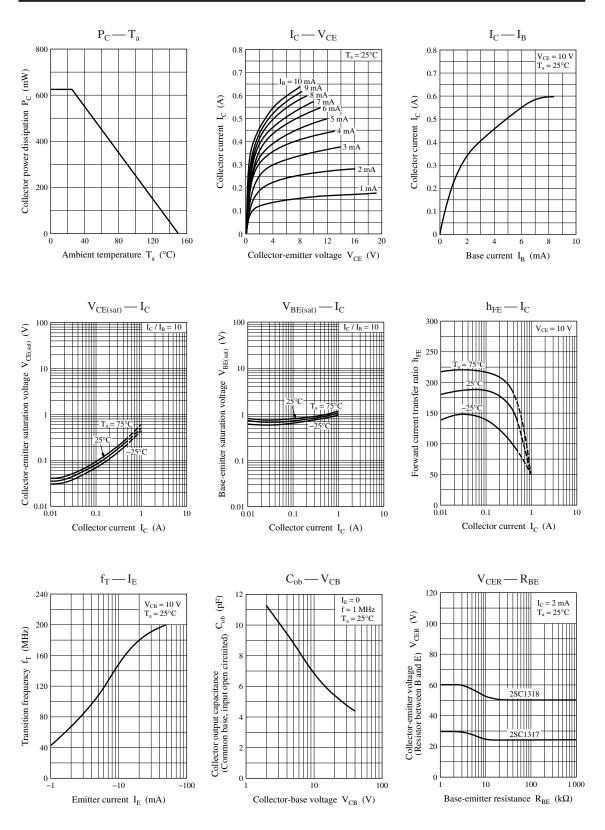
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

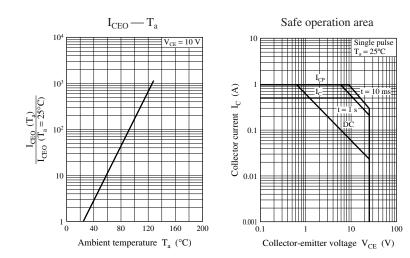
2. *1: Pulse measurement

*2: Rank classification

Rank	Q	R	S	
h _{FE1}	85 to 170	120 to 240	170 to 340	

Panasonic





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